



SYLLABUS

1. Data about the program of study

1.1	Institution	The Technical University of Cluj-Napoca				
1.2	Faculty	Electronics, Telecommunications and Information Technology				
1.3	Department	Applied Electronics				
1.4	Field of study	Electronics and Telecommunications Engineering				
1.5	Cycle of study	Bachelor of Science				
1.6	Program of study/Qualification	Technologies and Telecommunication Systems				
1.7	Form of education	Full time				
1.8	Subject code	TST-E48.20				

2. Data about the subject

2.1	Subject name	Applied Electronics				
2.2	Subject area	Electronics and Telecommunications Engineering				
2.3	Course responsible/lecturer	Assistant Professor Liviu Marin Viman, PhD				
2.4	Teachers in charge of applications	ners in charge of applications Assistant Professor Liviu Marin Viman, PhD				
2.5	Year of study IV 2.6 Semester 1	2.7 Assessment Verif. 2.8 Subject category DS/DOP				

3. Estimated total time

Year/ Sem.	Subject name	No. of	Course	Ap	plic	cations	Course	Ap	oplica	ations	Indiv. study	LAL	dits
		wee	[hours/week]		[hours/sem.]				6	Cred			
		ks		S	L	Р		S	L	Р		Г	U
IV/I	Applied Electronics	14	2		2		28		28		48	104	4

3.1 Number of hours per week	4	3.2	of which, course	2	3.3	applications	2
3.4 Total hours in the curriculum	56	3.5	of which, course	28	3.6	applications	28
Individual study							Hours
Manual, lecture material and notes, bibliography						26	
Supplementary study in the library, online and in the field						4	
Preparation for seminars/laboratory works, homework, reports, portfolios, essays						14	
Tutoring						2	
Exams and tests						2	
Other activities						-	
3.7 Total hours of individual stur	dv	18					

3.7	Total Hours of Individual Study	40
3.8	Total hours per semester	104
3.9	Number of credit points	4

4. Pre-requisites (where appropriate)

4.1	Curriculum	Spectral analysis of signals, sampling and quantization of signals. Analysis and design of circuits with transistors and operational amplifiers. Getting of boolean algebra. Analysis and synthesis of combinational and sequential digital circuits.
4.2	Competence	Using the computers, the laboratory equipment (multimeter, oscilloscope, etc)

5. Requirements (where appropriate)

5.1	For the course	Amphitheatre, Cluj-Napoca
5.2	For the applications	Laboratory, Cluj-Napoca





6. Specific competences

	Theoretical knowledge (what the student must know):	 Spectral analysis of signals, sampling and quantization of signals. Analysis and design of circuits with transistors and operational amplifiers. Getting of boolean algebra. Analysis and synthesis of combinational and sequential digital circuits.
Professional competences	es: (what Acquired skills (what the ent the student is able to do): to handle)	 After completing the discipline, the students will be able to: understand how to represent the numbers in electronic systems, to recognize the most used codes, to apply the conversion algorithms of values between different codes; understand the significance of catalog parameters for DA and AD converters circuits; choose the type of circuit (operating principle) and the circuit (depending on the performance) suitable for a particular application; analyze, based on structure, the operation and performance of a data acquisition system; Develop the specification of the software program for data acquisition system; use the computer simulation programs and the laboratory instruments (virtual) (power supply, oscilloscope, logic analyzer, signal generator, multimeter) for troubleshooting and analysis of the data propagation in the data acquisition systems;
۵.	Acquired abilities: (what type of equipment the student is able to handle)	- use the data sheets (print or online) in order to select the appropriate circuit to a required application.
	In accordance with Grila1 and Grila2 RNCIS	C2. To apply basic methods for signal acquisition and processing C3. To apply knowledge, concepts and basic methods regarding computing systems' architecture, microprocessors, microcontrollers, programming languages and techniques
	competences (Grila1 and Grila2 RNCIS)	N.A.

7. Discipline objectives (as results from the key competences gained)

7.1	General objectives	Developing skills in the field of analysis and the design of mixed analog-digital circuits and data acquisition systems.
7.2	Specific objectives	 Assimilation of theoretical knowledge regarding the structure and the performance of the A/D and D/A conversion circuits. Assimilation of theoretical knowledge on the functioning and performances of the support circuits for DAC and ADC. Obtaining the necessary skills to: develop, designing (and computer aided design) and analyze the data acquisition systems.





8. Contents

Binary representations. Binary representations. Binary representations. 2 DAC (Digital to Analog Converter): definitions, static and dynamic parameters, errors. Binary representations. Binary representations. 3 Weighted resistor networks. R/2R resistor networks. Crouts: caracteristics, applications. Binary representations. Binary representations. 4 Examples of intergrated DAC circuits: caracteristics, applications. Binary representation of intergrated DAC signal conditioning circuits. Binary representation of the temperature sensors. The design of data acquisition systems for instrumentation Binary representation of integers. Binary representation of integers. 10 Principles of measurement of the final exam. Binary representation of integers. Notes 12 Software for the data acquisition systems. PCB designing. Terms of design for user interaction. Binary representation of integers. Notes 13 Technology of the data acquisition systems. Teaching methods. Binary representation of integers. Binary representation. Binary representation. Binary representation.	8.1	. Lecture (syllabus)	Teaching methods	Notes				
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- 4. L. Viman. Applied Electronics (course slides, laboratories, problem examples, exam subjects)
- 5. M. Dăbâcan, L. Viman "Data Acquisition Systems Fundamentals Lab Themes ", UTCN, site:
 - http://www.ael.utcluj.ro/ORGANIZARE/curs_BSAD.HTML, 45 pagini, Cluj-Napoca, 2003.
 - 9. Bridging course contents with the expectations of the representatives of the community, professional associations and employers in the field

Competences acquired will be used in the following COR occupations (Electronics Engineer; Telecommunications Engineer; Electronics Design Engineer; System and Computer Design Engineer; Communications Design Engineer) or in the new occupations proposed to be included in COR (Sale Support Engineer; Multimedia Applications Developer; Network Engineer; Communications Systems Test Engineer; Project Manager; Traffic Engineer; Communications Systems Consultant).





10. Evaluations

Activity type	10.1	Assessment criteria	10.2	Assessment	10.3	Weight in the		
				methods		final grade		
Course		The level of acquired theoretical knowledge and practical skills		Summative evaluation written exams (E1 and E2)		65%		
Applications		The level of acquired abilities		practical lab test (T1, T2, T3 and T4)		35%		
10.4 Minimum standard of performance								
L≥5 (L=(T1+T2	L≥5 (L=(T1+T2+T3+T4)/4) and E1,E2≥4 and NF≥4.5 where NF=0.35*L +0.65*(E1+E2)/2.							

Date of filling in 26.01.2015

Course responsible Assist. Prof. Liviu Viman, PhD Teachers in charge of applications Assist. Prof. Liviu Viman, PhD

Date of approval in the department 26.01.2015

Head of department Prof. Dorin Petreus, PhD